

Power MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	650					
R _{DS(on)} (Ω)	V _{GS} = 10 V	1.8				
Q _g (Max.) (nC)	48					
Q _{gs} (nC)	12					
Q _{gd} (nC)	19					
Configuration	Single					

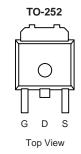
FEATURES

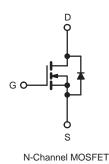
• Low Gate Charge Qg Results in Simple Drive Requirement



COMPLIANT

- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- · Fully Characterized Capacitance and Avalanche Voltage and Current
- Compliant to RoHS directive 2002/95/EC





ABSOLUTE MAXIMUM RATINGS $T_C = 25 \text{ °C}$, unless otherwise noted PARAMETER SYMBOL LIMIT UNIT **Drain-Source Voltage** V_{DS} 650 V Gate-Source Voltage ± 30 V_{GS} $T_C = 25 \degree C$ Continuous Drain Currente 4.5 V_{GS} at 10 V I_D $T_C = 100 \circ C$ **Continuous Drain Current** 4.2 А Pulsed Drain Current^a I_{DM} 18 Linear Derating Factor 0.48 W/°C E_{AS} Single Pulse Avalanche Energy^b 325 mJ 4 А Repetitive Avalanche Current^a I_{AR} Repetitive Avalanche Energy^a E_{AR} 6 mJ Maximum Power Dissipation T_C = 25 °C P_D 60 W Peak Diode Recovery dV/dtc dV/dt 2.8 V/ns Operating Junction and Storage Temperature Range - 55 to + 150 T_J, T_{stg} °C Soldering Recommendations (Peak Temperature)^d for 10 s 300 10 lbf · in Mounting Torque 6-32 or M3 screw 1.1 N · m

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Starting T_J = 25 °C, L = 24 mH, R_G = 25 Ω , I_{AS} = 3.2 A (see fig. 12).

c. $I_{SD} \le 3.2$ Å, dl/dt ≤ 90 Å/µs, $V_{DD} \le V_{DS}$, $T_J \le 150$ °C.

- d. 1.6 mm from case.
- e. Drain current limited by maximum junction temperature.



THERMAL RESISTANCE RA	TINGS	- I				1		
PARAMETER	SYMBOL	TYP	-	MAX.		UNIT		
Maximum Junction-to-Ambient	R _{thJA}	-		65		°C/W		
Maximum Junction-to-Case (Drain)	R _{thJC}	- 2.1			0,11			
SPECIFICATIONS T _J = 25 °C,	unless other	vise noted						
PARAMETER	SYMBOL			ONS	MIN.	TYP.	MAX.	UNIT
Static	I				1		1	
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} :	= 0 V, I _D = 2	50 µA	650	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C, I	_D = 1 mA ^d	-	670	-	mV/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D = 2	50 µA	2.5	-	5.0	V
Gate-Source Leakage	I _{GSS}		$V_{GS} = \pm 30 \text{ V}$		-	-	± 100	nA
Zana Osta Malta na Dasia Osmaal		V _{DS} =	650 V, V _{GS}	= 0 V	-	-	25	μA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 520 V	0 V, V _{GS} = 0 V, T _J = 125 °C	T _J = 125 °C	-	-	250	
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D :	= 3.1 A ^b	-	-	2.1	Ω
Forward Transconductance	9 _{fs}	V _{DS}	= 50 V, I _D =	3.1 A	3.9	-	-	S
Dynamic					•			
Input Capacitance	C _{iss}		$V_{GS} = 0 V,$		-	1417	-	
Output Capacitance	C _{oss}	$V_{GS} = 0.0,$ $V_{DS} = 25 V,$ f = 1.0 MHz, see fig. 5		-	177	-		
Reverse Transfer Capacitance	C _{rss}			-	7.0	-		
	0		V _{DS} = 1.0	V, f = 1.0 MHz	-	1912	-	pF
Output Capacitance	C _{oss}	$V_{GS} = 0 V$	V _{DS} = 520	V _{DS} = 520 V, f = 1.0 MHz	-	48	-	
Effective Output Capacitance	Coss eff.		$V_{DS} = 0 V \text{ to } 520 V^{c}$		-	84	-	1
Total Gate Charge	Qg				-	-	48	
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V	$I_D = 3.2 \text{ A}, V_{DS} = 400 \text{ V}$ see fig. 6 and 13^{b}		-	-	12	nC
Gate-Drain Charge	Q _{gd}				-	-	19	
Turn-On Delay Time	t _{d(on)}				-	14	-	1
Rise Time	t _r	$V_{DD} = 325 \text{ V}, I_D = 3.2 \text{ A} \\ R_G = 9.1 \Omega, R_D = 62 \Omega, \\ \text{see fig. 10^b}$		-	20	-	- ns	
Turn-Off Delay Time	t _{d(off)}			-	34	-		
Fall Time	t _f	1 Ŭ			-	18		-
Drain-Source Body Diode Characteristic	cs							
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	4	- A	
Pulsed Diode Forward Current ^a	I _{SM}			-	-	21		
Body Diode Voltage	V _{SD}	$T_J = 25 \text{ °C}, I_S = 3.2 \text{ A}, V_{GS} = 0 \text{ V}^{b}$		-	-	1.5	V	
Body Diode Reverse Recovery Time	t _{rr}	$T_J = 25 \text{ °C}, I_F = 3.2 \text{ A}, \text{ dl/dt} = 100 \text{ A/}\mu\text{s}^b$		-	493	739	ns	
Body Diode Reverse Recovery Charge	Q _{rr}			-	2.1	3.2	μC	
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)						

Notes

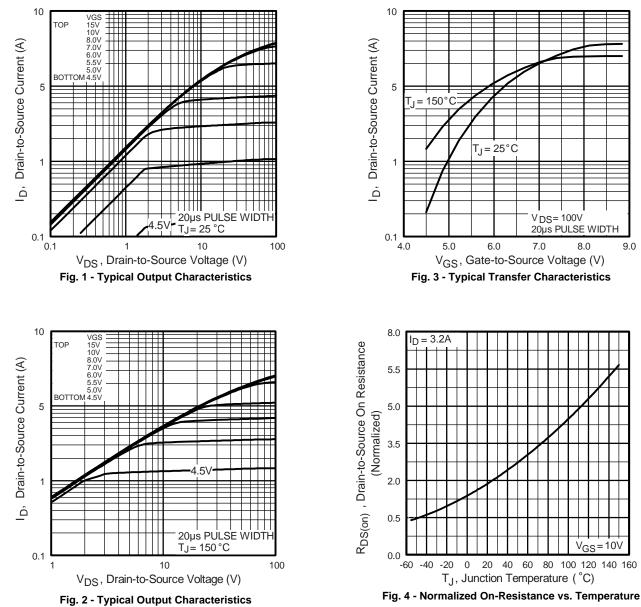
a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width \leq 300 µs; duty cycle \leq 2 %.

c. C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DS} .

d. t = 60 s, f = 60 Hz.





TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

VBE165R04



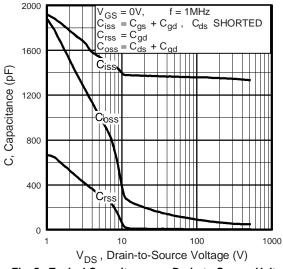


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

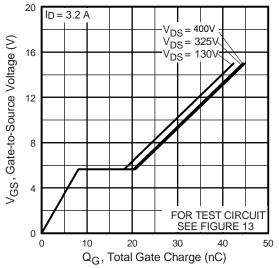


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

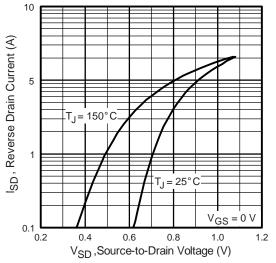
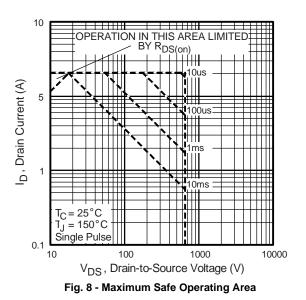


Fig. 7 - Typical Source-Drain Diode Forward Voltage



VBE165R04



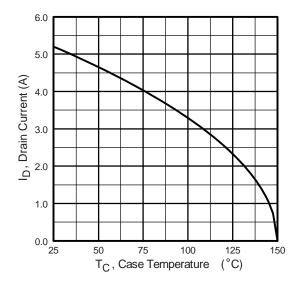


Fig. 9 - Maximum Drain Current vs. Case Temperature

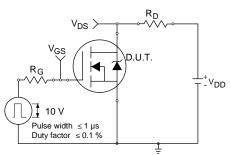


Fig. 10a - Switching Time Test Circuit

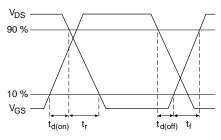
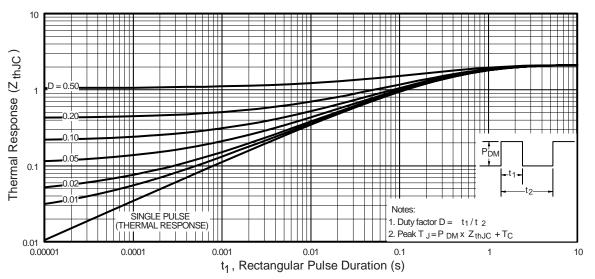


Fig. 10b - Switching Time Waveforms





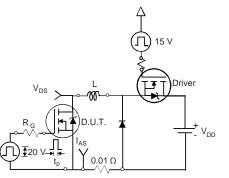


Fig. 12a - Unclamped Inductive Test Circuit

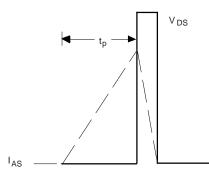


Fig. 12b - Unclamped Inductive Waveforms



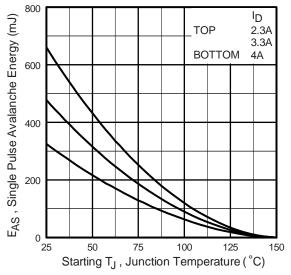


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

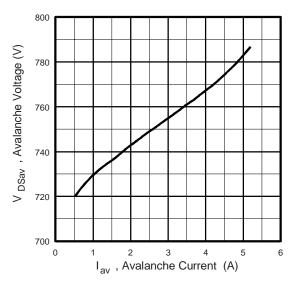


Fig. 12d - Typical Drain-to Source Voltage vs. Avalanche Current

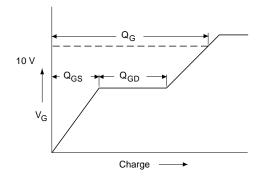


Fig. 13a - Basic Gate Charge Waveform

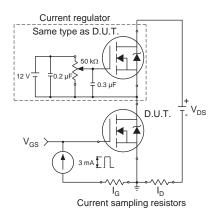
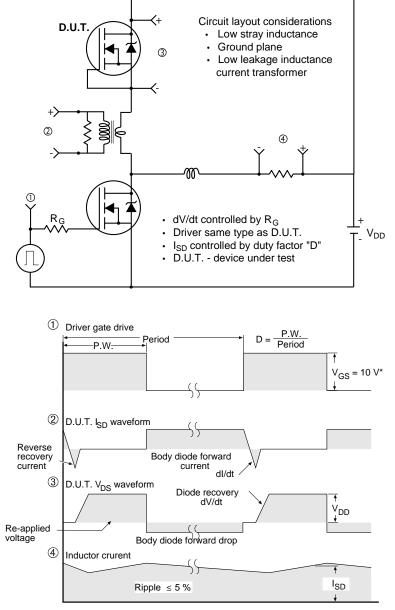


Fig. 13b - Gate Charge Test Circuit





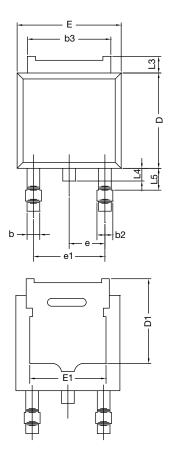
Peak Diode Recovery dV/dt Test Circuit

* V_{GS} = 5 V for logic level devices

Fig. 14 - For N-Channel



TO-252AA CASE OUTLINE





	MILLIMETERS		INCHES			
DIM.	MIN.	MAX.	MIN.	MAX.		
А	2.18	2.38	0.086	0.094		
A1	-	0.127	-	0.005		
b	0.64	0.88	0.025	0.035		
b2	0.76	1.14	0.030	0.045		
b3	4.95	5.46	0.195	0.215		
С	0.46	0.61	0.018	0.024		
C2	0.46	0.89	0.018	0.035		
D	5.97	6.22	0.235	0.245		
D1	5.21	-	0.205	-		
E	6.35	6.73	0.250	0.265		
E1	4.32	-	0.170	-		
Н	9.40	10.41	0.370	0.410		
е	2.28	2.28 BSC		0.090 BSC		
e1	4.56 BSC		0.180 BSC			
L	1.40	1.78	0.055	0.070		
L3	0.89	1.27	0.035	0.050		
L4	-	1.02	-	0.040		
L5	1.14	1.52	0.045	0.060		
ECN: X12-0247-Rev. M, 24-Dec-12 DWG: 5347						

Note

• Dimension L3 is for reference only.



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